

# Spring-loaded test probe

## GKS-967 305 130 A 1001 C

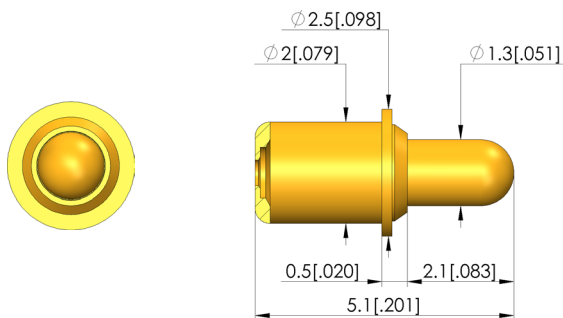
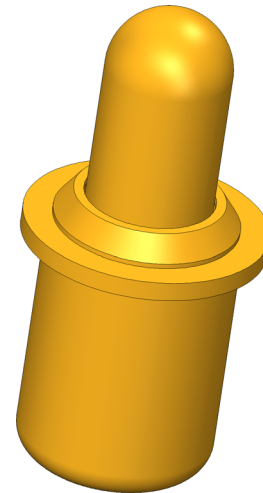
Item GKS-967-0039



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- Short-stroke probes ensure a reliable signal and power supply, as well as a quick exchange of assemblies in case of maintenance
- For the construction of easily separable electronic interfaces, such as in charging trays for electronic devices
- Particularly suitable for use in applications where space for overall length is limited
- Compensation of possible height and component tolerances
- Stainless steel versions for temperatures from -100 °C up to +200 °C available



### General data

Product group:	Assorted test probes
Sub-product group:	Short stroke GKS / charge and transfer GKS
Series:	GKS-967
Grid:	3 mm [118 mil]
Contacting from:	Pad, Female connector
Magnetic:	Yes
Installation type:	Plug-in
Quick-exchange system:	Yes
Adjustable installation height:	No
Non-rotating:	No
Compatible receptacle(s):	KS-967, KS-967 25, KS-967 50
Min. temperature:	- 100 °C [- 212 °F]
Max. temperature:	+ 200 °C [+ 392 °F]
RoHS-compliant:	RoHS-3;6c

### Electrical data

Current load capacity / rated current:	5 A
Typical resistance (Ri):	<100 mOhm

### Mechanical data

Total length:	5.1 mm [.200 in]
Barrel diameter:	2 mm [.078 in]
Maximum stroke:	1.2 mm [.047 in]
Spring pre-load:	0.29 N [1.04 ozf]
Collar height:	01
Spring force at working stroke:	1 N [3.59 ozf]
Recommended working stroke:	1 mm [.039 in]

### Tip style data

Tip style:	05 bullet-nosed (full radius)
Tip diameter:	1.3 mm [.051 in]
Tip style surface:	A gold
Tip style material:	3 CuBe

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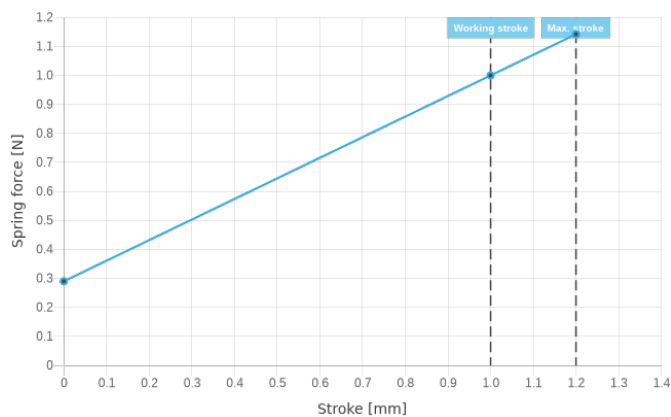
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